DESCRIPTION

This book/CD package provides a reference on electron energy loss spectrometry (EELS) with the transmission electron microscope, an established technique for chemical and structural analysis of thin specimens in a transmission electron microscope. Describing the issues of instrumentation, data acquisition, and data analysis, the authors apply this technique to several classes of materials, namely ceramics, metals, polymers, minerals, semiconductors, and magnetic materials. The accompanying CD-ROM consists of a compendium of experimental spectra.

ABOUT THE AUTHOR

Channing C. Ahn earned his PhD in Physics at the University of Bristol, UK, in 1986. He is presently a Professor at the California Institute of Technology.